Stanislav Jurecka

List of Publications by Year
in descending order

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30	292	1163117 8	888059 17
papers	citations	h-index	g-index

31	31	31	183
all docs	docs citations	times ranked	citing authors

#	Article	IF	Citations
1	Microstructure and optical properties of etched silicon layers for photovoltaic applications. , 2022, , .		0
2	Effect of annealing on the micromorphology and corrosion properties of Ti/SS thin films. Superlattices and Microstructures, 2020, 146, 106681.	3.1	29
3	Multifractal and optical bandgap characterization of Ta2O5 thin films deposited by electron gun method. Optical and Quantum Electronics, 2020, 52, 1.	3.3	46
4	Microstructure and optical properties of layers formed by anodic etching of silicon. AIP Conference Proceedings, 2019, , .	0.4	1
5	Determination of thickness of electrochemically etched Si layers passivated by Si3N4 by analysis of the experimental spectral reflectance. AIP Conference Proceedings, 2019, , .	0.4	1
6	Minkowski functional characterization and fractal analysis of surfaces of titanium nitride films. Materials Research Express, 2019, 6, 086463.	1.6	126
7	Prepared Ïƒ-MnO2 thin films by chemical bath deposition methods and study of its optical and microstructure properties. Optical and Quantum Electronics, 2019, 51, 1.	3.3	10
8	Thickness and tensile stress determination of black silicon layers by spectral reflectance and Raman scattering. Journal of Electrical Engineering, 2019, 70, 51-57.	0.7	1
9	Black silicon â€" correlation between microstructure and Raman scattering. Journal of Electrical Engineering, 2019, 70, 58-64.	0.7	0
10	Investigation of morphological and optical properties of nanostructured layers formed by the SSCT etching of silicon. Applied Surface Science, 2018, 461, 72-77.	6.1	1
11	Properties of nanostructured layers formed on silicon. AIP Conference Proceedings, 2018, , .	0.4	0
12	Microstructure and optical properties of black silicon layers. , 2018, , .		0
13	Multifractal analysis and optical properties of nanostructured silicon layers. Applied Surface Science, 2017, 395, 150-156.	6.1	12
14	Properties of nanocrystalline Si layers embedded in structure of solar cell. Journal of Electrical Engineering, 2017, 68, 48-52.	0.7	0
15	Reflectance analysis of porosity gradient in nanostructured silicon layers. , 2017, , .		0
16	Statistical and Fractal Analysis of Random Height Function. Communications - Scientific Letters of the University of Zilina, 2017, 19, 57-61.	0.6	0
17	Analysis of linear and nonlinear effects in optical fiber. , 2016, , .		0
18	Multifractal analysis of textured silicon surfaces. Applied Surface Science, 2014, 301, 46-50.	6.1	18

#	Article	IF	Citations
19	Measuring capacitance of various types of structures. , 2014, , .		3
20	Passivation of Si-based structures in HCN and KCN solutions. Applied Surface Science, 2012, 258, 8397-8405.	6.1	9
21	Properties of charge states in MOS structure with ultrathin oxide layer. Applied Surface Science, 2012, 258, 8409-8414.	6.1	3
22	Study of density of interface states in MOS structure with ultrathin NAOS oxide. Open Physics, 2012, 10, .	1.7	4
23	The cavity resonator design: stochastic optimization of the transmission line method. Proceedings of SPIE, 2011, , .	0.8	0
24	Study of microstructural and optical properties of a-Si:H thin films. , 2010, , .		1
25	On the influence of the surface roughness onto the ultrathin SiO2/Si structure properties. Applied Surface Science, 2010, 256, 5623-5628.	6.1	12
26	On Topographic Properties of Semiconductor Surfaces and Thin Film Systems. Materials Science Forum, 2009, 609, 275-279.	0.3	3
27	On determination of properties of ultrathin and very thin silicon oxide layers by FTIR and X - ray reflectivity. Materials Research Society Symposia Proceedings, 2008, 1066, 1.	0.1	2
28	Structural Characterization of Iron in Human Spleen. Materials Research Society Symposia Proceedings, 2008, 1132, 1.	0.1	2
29	On formation of thin SiO2/a-Si:H interface when biased oxidized semiconductor surface interacts with plasma or liquid solution. Open Physics, 2007, 5, .	1.7	1
30	<title>Investigation of electrical, structural, and optical properties of very thin oxide/a-Si:H/c-Si interfaces passivated by cyanide treatment</title>. , 2004, 5774, 481.		1